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INFORMATION DISCLOSURE STATEMENT BY APPLICANT	Application Number	10/719217	
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JUN 0 1 2004 &	First Named Inventor	Forbes, Leonard	
2004 60	Group Art Unit	2824	
TO TO THE WAY	Examiner Name	Nguyen, Hien	
Sheet 1 of 2	Attorney Docket No: 303.620US2		

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	Examiner Name	Nguyen, Hien	
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